Application/Control No. Applicant(s)/Patent Under Reexamination 10/600,065 SHIEH ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 2824 Dang T. Nguyen **U.S. PATENT DOCUMENTS** Date **Document Number** Name Classification Country Code-Number-Kind Code MM-YYYY US-2003/0206446 A1 11-2003 Yamada, Shigekazu 365/185.24 Α US-6,639,849 B2 10-2003 Takahashi et al. 365/189.07 В US-С D US-US-Ε US-F US-G US-Н US-١ J US-US-Κ US-US-FOREIGN PATENT DOCUMENTS Date **Document Number** Classification Name Country Country Code-Number-Kind Code MM-YYYY Ν 0 Ρ Q R s Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

٧

W